



## N-Channel Enhancement MOSFET

### Features

- Drain-Source Breakdown Voltage  $V_{DS}$  30V
- Drain-Source On-Resistance  
 $R_{DS(ON)}$  4m $\Omega$ , at  $V_{GS}= 10V, I_D= 30A$   
 $R_{DS(ON)}$  7m $\Omega$ , at  $V_{GS}= 4.5V, I_D= 15A$
- *Continuous Drain Current* at  $T_C=25^\circ C I_D =74A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free
- ESD Protection

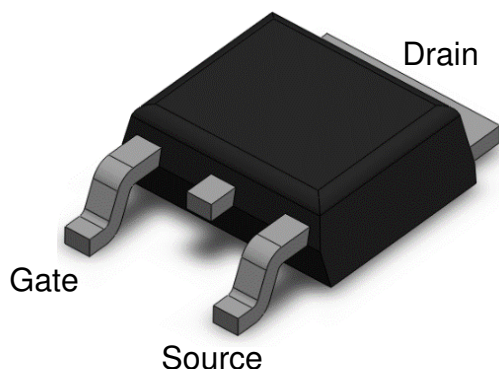
### Applications

- Power Management in
- Battery Powered System
- DC/DC Converter
- Load Switch

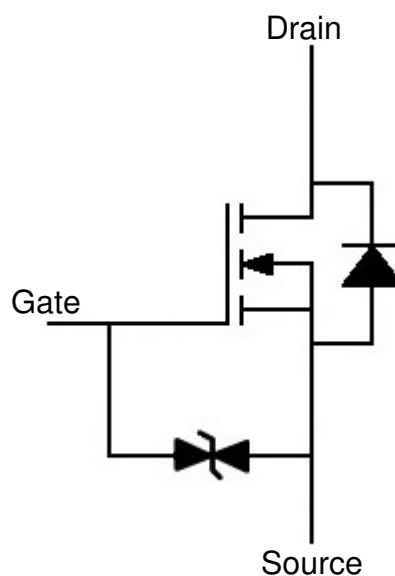
### Description

The CTH7403NS-T52 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance.

### Package Outline



### Schematic





**CTH7403NS-T52**

**N-Channel Enhancement MOSFET**

**Absolute Maximum Rating at 25°C**

Symbol	Parameters	Test Conditions	Min	Note
V <sub>DS</sub>	Drain-Source Voltage	30	V	
V <sub>GS</sub>	Gate-Source Voltage	±20	V	
I <sub>D</sub>	Continuous Drain Current @T <sub>C</sub> =25°C	74	A	1
I <sub>DM</sub>	Pulsed Drain Current	296	A	1
P <sub>D</sub>	Total Power Dissipation @T <sub>C</sub> =25°C	42	W	2
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C	
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C	

**Thermal Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R <sub>θJC</sub>	Thermal Resistance Junction-Case		--	--	3.0	°C /W	1,4



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Electrical Characteristics  $T_A = 25^\circ\text{C}$  (unless otherwise specified)

## Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
B <sub>VDS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	30	-	-	V	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V	-	-	1	μA	
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	-	-	±10	μA	

## On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R <sub>DS(ON)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 30A	-	4	4.8	mΩ	3
R <sub>DS(ON)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 15A	-	7	9	mΩ	3
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250μA	1.2	-	3.0	V	

## Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C <sub>ISS</sub>	Input Capacitance	V <sub>GS</sub> = 0V,	-	2400	2700	pF	
C <sub>OSS</sub>	Output Capacitance	V <sub>DS</sub> = 15V	-	350	-		
C <sub>RSS</sub>	Reverse Transfer Capacitance	f = 1MHz	-	110	-		

## Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
T <sub>D(ON)</sub>	Turn-On Delay Time	V <sub>DS</sub> = 15V ,	-	23	-	ns	
T <sub>R</sub>	Rise Time	V <sub>GS</sub> = 10V ,	-	17	-		
T <sub>D(OFF)</sub>	Turn-Off Delay Time	R <sub>G</sub> = 6Ω ,	-	76	-		
T <sub>F</sub>	Fall Time	R <sub>L</sub> = 15Ω ,	-	15	-		
Q <sub>G</sub>	Total Gate Charge	V <sub>DS</sub> = 15V ,	-	27	-	nC	
Q <sub>GS</sub>	Gate-Source Charge	V <sub>GS</sub> = 4.5V ,	-	11	-		
Q <sub>GD</sub>	Gate-Drain (Miller) Charge	I <sub>D</sub> = 17A ,	-	14	-		



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#### Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$V_{SD}$	Body Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 2.7A$	-	0.8	1.2	V	1
$I_{SD}$	Body Diode Continuous Current		-	-	2.7	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
3. Thermal Resistance follow JESD51-3.



### Typical Characteristic Curves

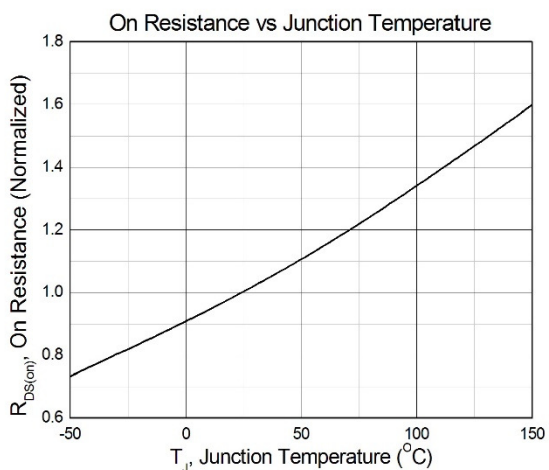


Figure 1

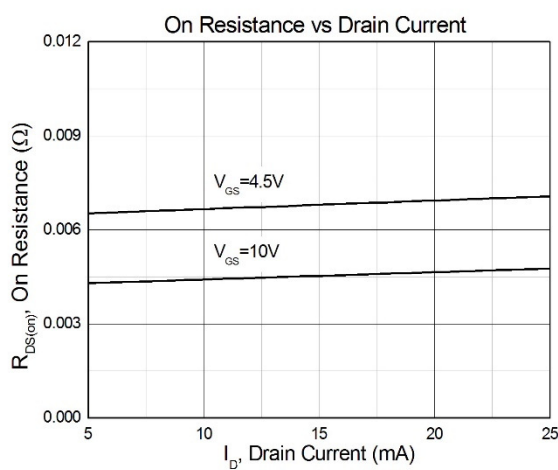


Figure 2

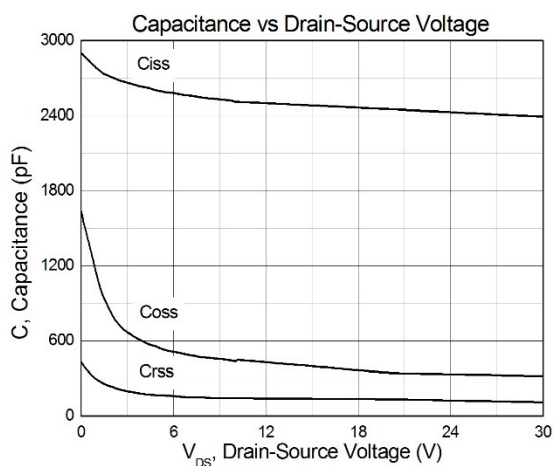


Figure 3

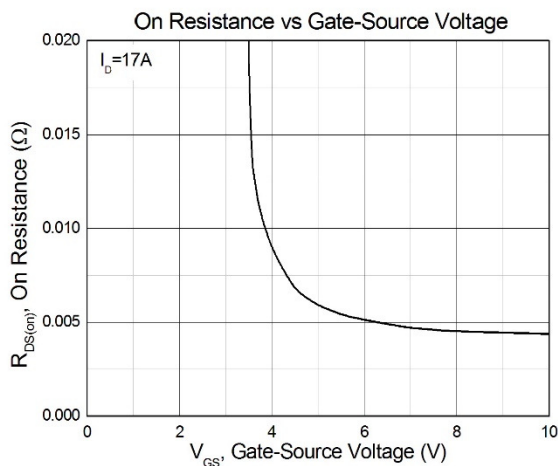


Figure 4

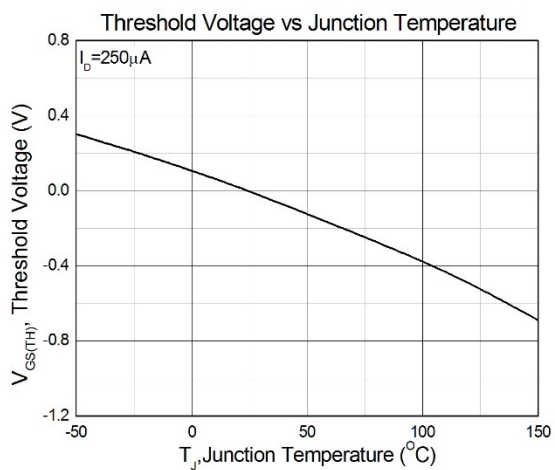


Figure 5

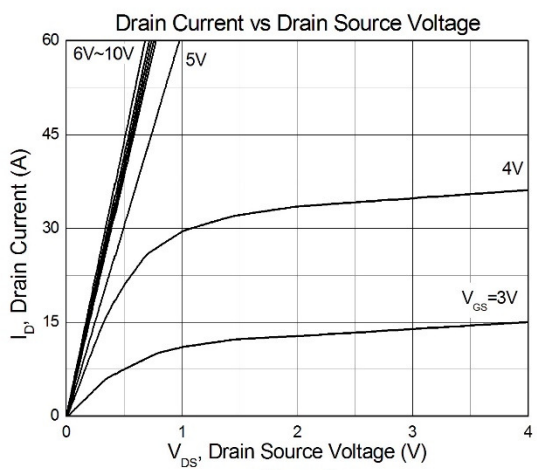


Figure 6

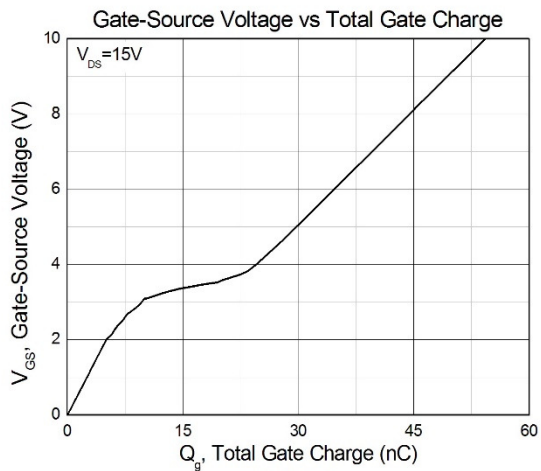


Figure 7

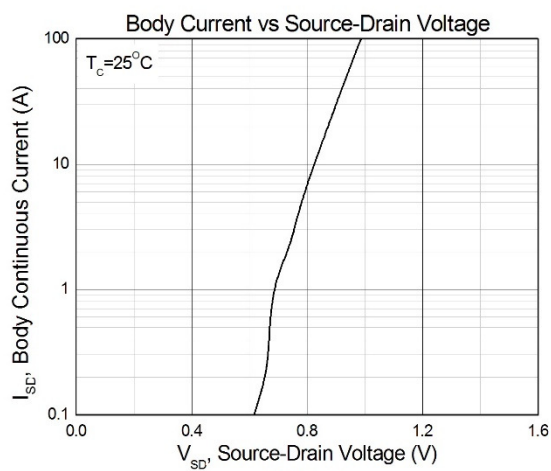


Figure 8



Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

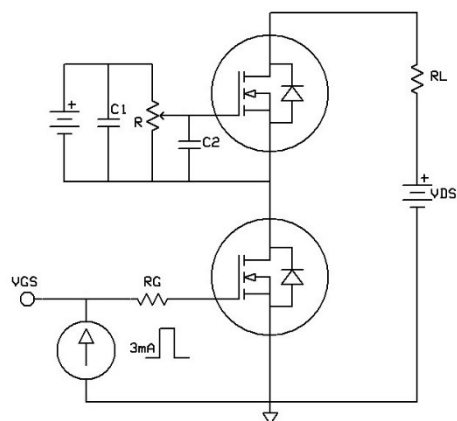


Figure 10: Gate Charge Waveform

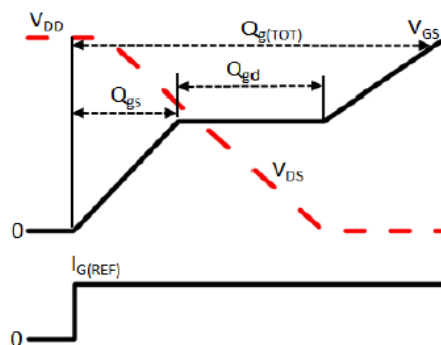


Figure 11: Switching Time Test Circuit

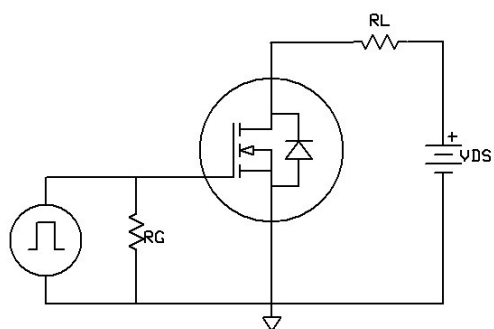
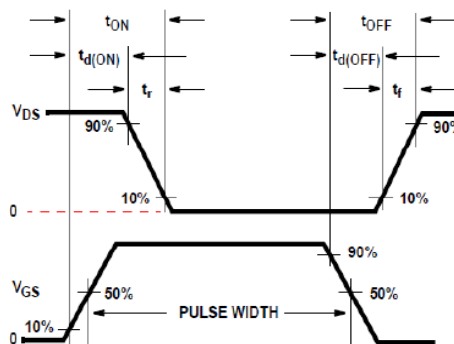
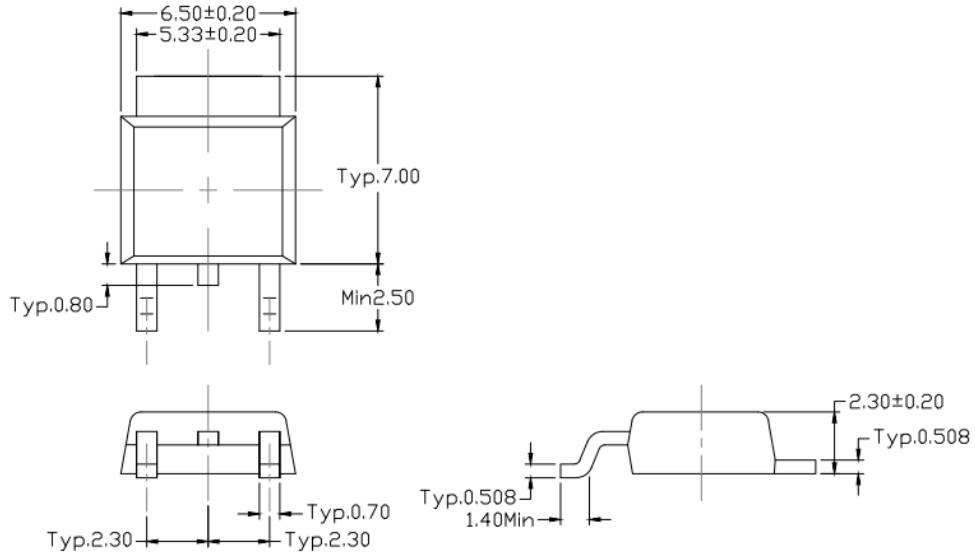


Figure 12: Switching Time Waveform



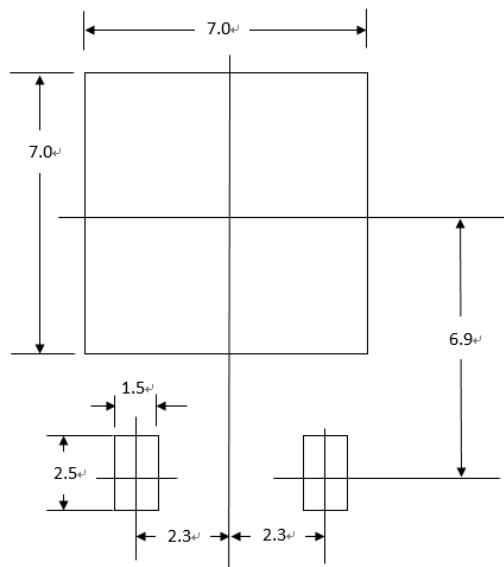


Package Dimension (TO-252)



Dimensions in mm unless otherwise stated

Recommended pad layout for surface mount leadform



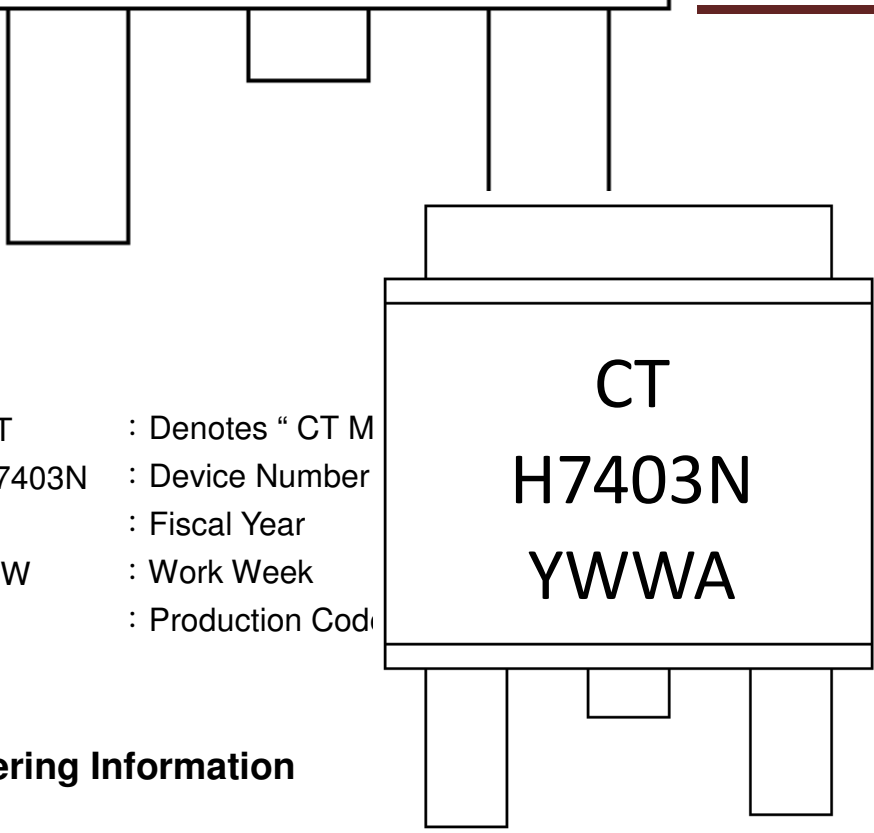
Dimensions in mm unless otherwise stated



CTH7403NS  
YWWA

CTH7403NS-T52

Channel Enhancement MOSFET



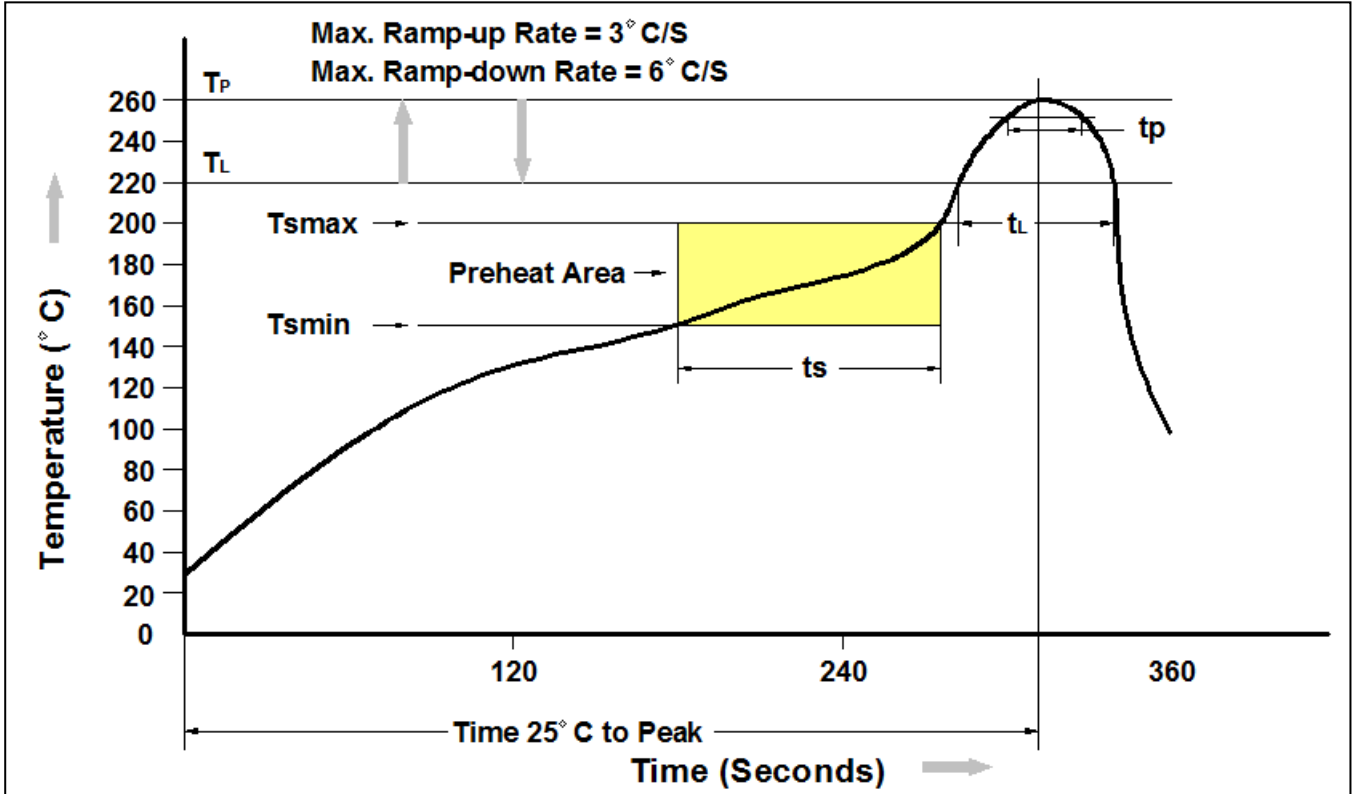
CT : Denotes "CT M  
H7403N : Device Number  
Y : Fiscal Year  
WW : Work Week  
A : Production Code

**Ordering Information**

Part Number	Description	Quantity
CTH7403NS-T52	TO-252 Reel	2500 pcs



Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T <sub>min</sub> )	150 °C
Temperature Max. (T <sub>max</sub> )	200 °C
Time (t <sub>s</sub> ) from (T <sub>min</sub> to T <sub>max</sub> )	60-120 seconds
Ramp-up Rate (t <sub>L</sub> to t <sub>P</sub> )	3°C/second max.
Liquidous Temperature (T <sub>L</sub> )	217 °C
Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub> )	60 – 150 seconds
Peak Body Package Temperature	260 °C +0 °C / -5 °C
Time (t <sub>P</sub> ) within 5 °C of 260 °C	30 seconds
Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )	6°C/second max
Time 25 °C to Peak Temperature	8 minutes max.



CTH7403NS-T52

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